2nd Semiconductor Traceability and Provenance Workshop -- Agenda			
Agenda Item	**Who**	**Time (min)**	**Time (start, finish)**
Welcome and Workshop Briefing	James St. Pierre (NIST)	5	8:15 - 8:30 am
Overview of the Meeting Objectives and Desired Outcomes	Kostas Amberiadis & Sanjay Rekhi (NIST)	10	
Industry-Wide Guidelines on Semiconductor Traceability and Provenance	Melissa Grupen-Shemansky (SEMI)	20	8:30 - 9:50 am
	Melinda Reed & Forrest Shull (DoW)	20	
	Jeff Krieg (NSA)	20	
	Robert Kaster (Bosch)	20	
Morning Break		10	9:50 - 10:00 am
Industry-Wide Guidelines on Semiconductor Traceability and Provenance	Bill Mazzara (Stellantis)	20	10:00 - 12:00 am
	Jon Azen (Qualcomm)	20	
	John Wallrabenstein (Analog Devices)	20	
	Alex Tzonkov (AMD) Jeff Andersen (Google) Nicole Bates (Microsoft) Jacob Wright (Meta)	60	
Lunch Break		60	12:00 - 1:00 pm
Industry-Wide Guidelines on Semiconductor Traceability and Provenance	Joshua Schiffman (HP Inc)	20	1:00 - 1:40 pm
	David Sequino (OmniTrust)	20	
Panel Discussion -- Traceability Data Sharing: What is the Optimum Balance?	Nicole Bates (Microsoft) Prabhu Jayanna (AMD) Carl E McCants (Intel) Daniel O'Laughlin (Qualcomm) John Wallrabenstein (Analog Devices) Jacob Wright (Meta) Rebecca McWhite (Panel Moderator, NIST)	60	1:40 - 2:40 pm
Afternoon Break		10	2:40 - 2:50 pm
Breakout Sessions	3 Breakout Sessions	60	2:50 - 3:50 pm
Summarize Breakout Sessions	Kostas Amberiadis (NIST) Sanjay Rekhi (NIST) Ankur Srivastava (UMD)	25	3:50 - 4:15 pm
Closing Remarks and Adjournment	Kostas Amberiadis & Sanjay Rekhi (NIST)	5	4:15 - 4:20 pm